



STFW69N65M5 STW69N65M5

N-channel 650 V, 0.037 Ω typ., 58 A MDmesh™ V Power MOSFET
in TO-3PF and TO-247 packages

Datasheet – production data

Features

| Order codes | V_{DSS} @ T_{Jmax} | $R_{DS(on)}$ max | I_D |
|-------------|------------------------|------------------|-------|
| STFW69N65M5 | 710 V | < 0.045 Ω | 58 A |
| STW69N65M5 | | | |

- Worldwide best $R_{DS(on)}$ * area
- Higher V_{DSS} rating and high dv/dt capability
- Excellent switching performance
- 100% avalanche tested

Applications

- Switching applications

Description

These devices are N-channel MDmesh™ V Power MOSFETs based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESH™ horizontal layout structure. The resulting product has extremely low on-resistance, which is unmatched among silicon-based Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency.

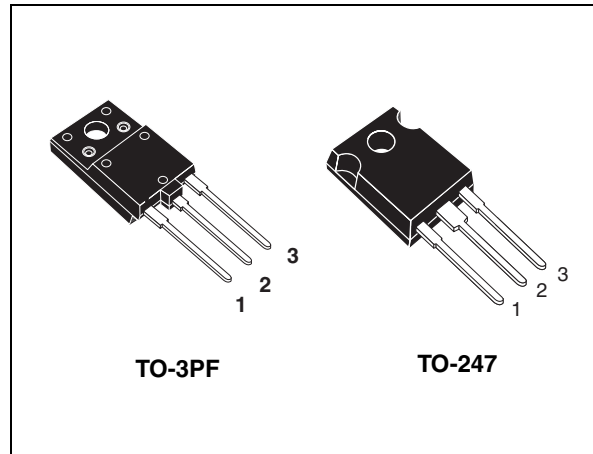


Figure 1. Internal schematic diagram

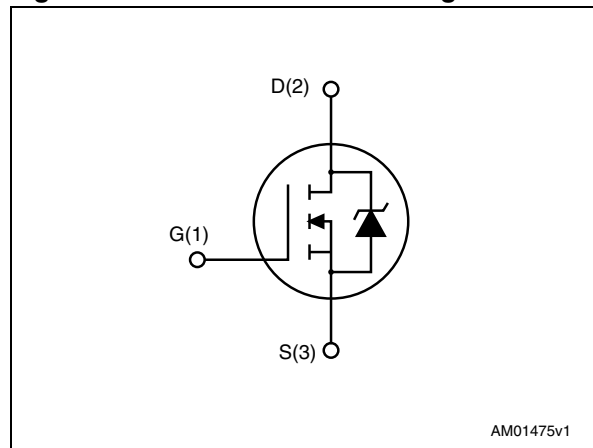


Table 1. Device summary

| Order codes | Marking | Package | Packaging |
|-------------|---------|---------|-----------|
| STFW69N65M5 | 69N65M5 | TO-3PF | Tube |
| STW69N65M5 | | TO-247 | |

Contents

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1 Electrical ratings

Table 2. Absolute maximum ratings

| Symbol | Parameter | Value | | Unit |
|-------------------------|---|---------------------|--------|------|
| | | TO-3PF | TO-247 | |
| V_{GS} | Gate-source voltage | ± 25 | | V |
| I_D | Drain current (continuous) at $T_C = 25\text{ °C}$ | 58 ⁽¹⁾ | 58 | A |
| I_D | Drain current (continuous) at $T_C = 100\text{ °C}$ | 36.5 ⁽¹⁾ | 36.5 | A |
| I_{DM} ⁽²⁾ | Drain current (pulsed) | 232 ⁽¹⁾ | 232 | A |
| P_{TOT} | Total dissipation at $T_C = 25\text{ °C}$ | 79 | 330 | W |
| dv/dt ⁽³⁾ | Peak diode recovery voltage slope | 15 | | V/ns |
| V_{ISO} | Insulation withstand voltage (RMS) from all three leads to external heat sink (t=1s; Tc=25°C) | 3500 | | V |
| T_{stg} | Storage temperature | - 55 to 150 | | °C |
| T_j | Max. operating junction temperature | 150 | | °C |

1. Limited by maximum junction temperature.

2. Pulse width limited by safe operating area

3. $I_{SD} \leq 58\text{ A}$, $di/dt \leq 400\text{ A}/\mu\text{s}$; $V_{DS\text{ peak}} < V_{(BR)DSS}$, $V_{DD}=400\text{ V}$

Table 3. Thermal data

| Symbol | Parameter | Value | | Unit |
|-----------------------|---|--------|--------|------|
| | | TO-3PF | TO-247 | |
| $R_{thj\text{-case}}$ | Thermal resistance junction-case max | 1.58 | 0.38 | °C/W |
| $R_{thj\text{-amb}}$ | Thermal resistance junction-ambient max | 50 | | °C/W |

Table 4. Avalanche characteristics

| Symbol | Parameter | Value | Unit |
|----------|---|-------|------|
| I_{AR} | Avalanche current, repetitive or not repetitive (pulse width limited by $T_{j\text{max}}$) | 12 | A |
| E_{AS} | Single pulse avalanche energy (starting $t_j=25\text{ °C}$, $I_d=I_{AR}$; $V_{dd}=50$) | 1410 | mJ |

2 Electrical characteristics

($T_C = 25\text{ °C}$ unless otherwise specified)

Table 5. On /off states

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---------------|--|--|------|-------|-----------|--------------------------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage | $I_D = 1\text{ mA}$, $V_{GS} = 0$ | 650 | | | V |
| I_{DSS} | Zero gate voltage drain current ($V_{GS} = 0$) | $V_{DS} = 650\text{ V}$ $V_{DS} = 650\text{ V}$, $T_C = 125\text{ °C}$ | | | 1 100 | μA μA |
| I_{GSS} | Gate-body leakage current ($V_{DS} = 0$) | $V_{GS} = \pm 25\text{ V}$ | | | ± 100 | nA |
| $V_{GS(th)}$ | Gate threshold voltage | $V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$ | 3 | 4 | 5 | V |
| $R_{DS(on)}$ | Static drain-source on-resistance | $V_{GS} = 10\text{ V}$, $I_D = 29\text{ A}$ | | 0.037 | 0.045 | Ω |

Table 6. Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-------------------|---------------------------------------|---|------|------|------|----------|
| C_{iss} | Input capacitance | $V_{DS} = 100\text{ V}$, $f = 1\text{ MHz}$, $V_{GS} = 0$ | - | 6420 | - | pF |
| C_{oss} | Output capacitance | | | 170 | | pF |
| C_{rss} | Reverse transfer capacitance | | | 11 | | pF |
| $C_{o(tr)}^{(1)}$ | Equivalent capacitance time related | $V_{DS} = 0\text{ to }520\text{ V}$, $V_{GS} = 0$ | - | 536 | - | pF |
| $C_{o(er)}^{(2)}$ | Equivalent capacitance energy related | | | 146 | | pF |
| R_G | Intrinsic gate resistance | $f = 1\text{ MHz}$ open drain | - | 1.2 | - | Ω |
| Q_g | Total gate charge | $V_{DD} = 520\text{ V}$, $I_D = 29\text{ A}$, $V_{GS} = 10\text{ V}$ (see Figure 18) | - | 143 | - | nC |
| Q_{gs} | Gate-source charge | | | 38 | | nC |
| Q_{gd} | Gate-drain charge | | | 64 | | nC |

1. Time related is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}
2. Energy related is defined as a constant equivalent capacitance giving the same stored energy as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 7. Switching times

| Symbol | Parameter | Test conditions | Min. | Typ. | Max | Unit |
|--------------|--------------------|---|------|------|-----|------|
| $t_{d(v)}$ | Voltage delay time | $V_{DD} = 400\text{ V}$, $I_D = 38\text{ A}$, | | 102 | | ns |
| $t_{r(v)}$ | Voltage rise time | $R_G = 4.7\ \Omega$, $V_{GS} = 10\text{ V}$ | - | 13.5 | - | ns |
| $t_{f(i)}$ | Current fall time | (see Figure 19 and | | 10 | | ns |
| $t_{c(off)}$ | Crossing time | Figure 22) | | 19 | | ns |

Table 8. Source drain diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------|-------------------------------|---|------|------|------|---------------|
| I_{SD} | Source-drain current | | - | | 58 | A |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) | | - | | 232 | A |
| $V_{SD}^{(2)}$ | Forward on voltage | $I_{SD} = 58\text{ A}$, $V_{GS} = 0$ | - | | 1.5 | V |
| t_{rr} | Reverse recovery time | $I_{SD} = 58\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$ | - | 480 | | ns |
| Q_{rr} | Reverse recovery charge | $V_{DD} = 100\text{ V}$ (see Figure 19) | | 11 | | μC |
| I_{RRM} | Reverse recovery current | | | 46 | | A |
| t_{rr} | Reverse recovery time | $I_{SD} = 58\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$ | - | 592 | | ns |
| Q_{rr} | Reverse recovery charge | $V_{DD} = 100\text{ V}$, $T_j = 150\text{ }^\circ\text{C}$ | | 16 | | μC |
| I_{RRM} | Reverse recovery current | (see Figure 19) | | 53 | | A |

1. Pulse width limited by safe operating area.

2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for TO-3PF

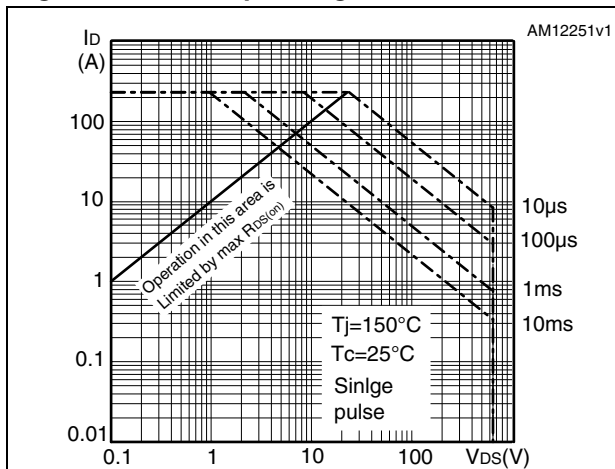


Figure 3. Thermal impedance for TO-3PF

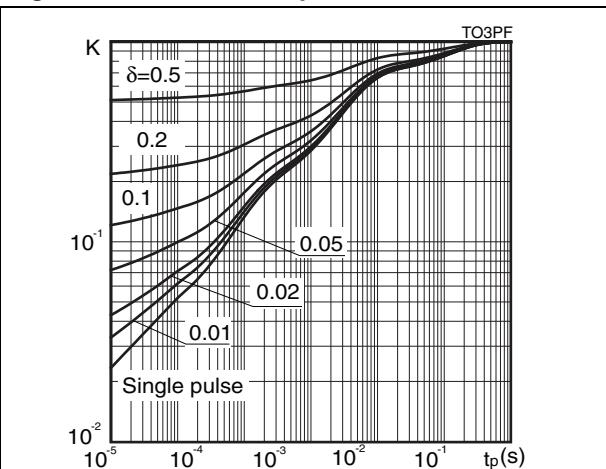


Figure 4. Safe operating area for TO-247

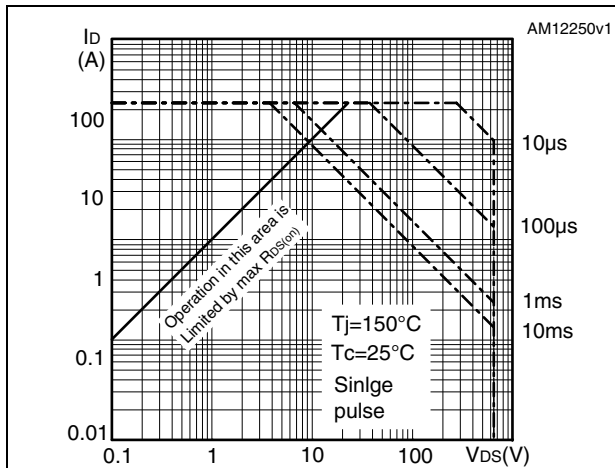


Figure 5. Thermal impedance for TO-247

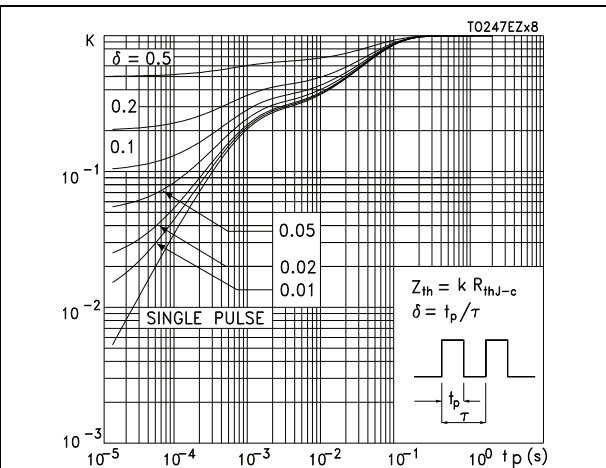


Figure 6. Output characteristics

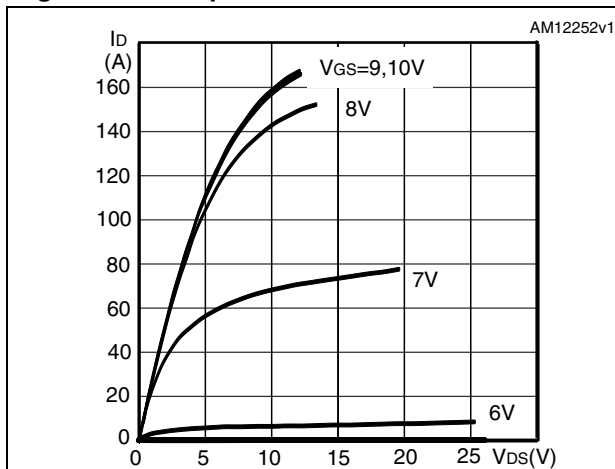


Figure 7. Transfer characteristics

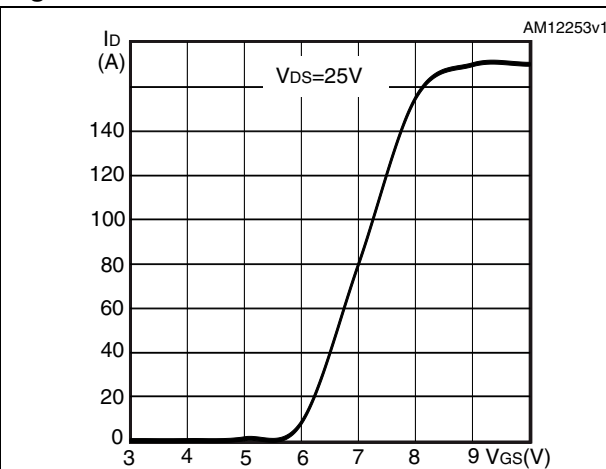


Figure 8. Gate charge vs gate-source voltage Figure 9. Static drain-source on-resistance

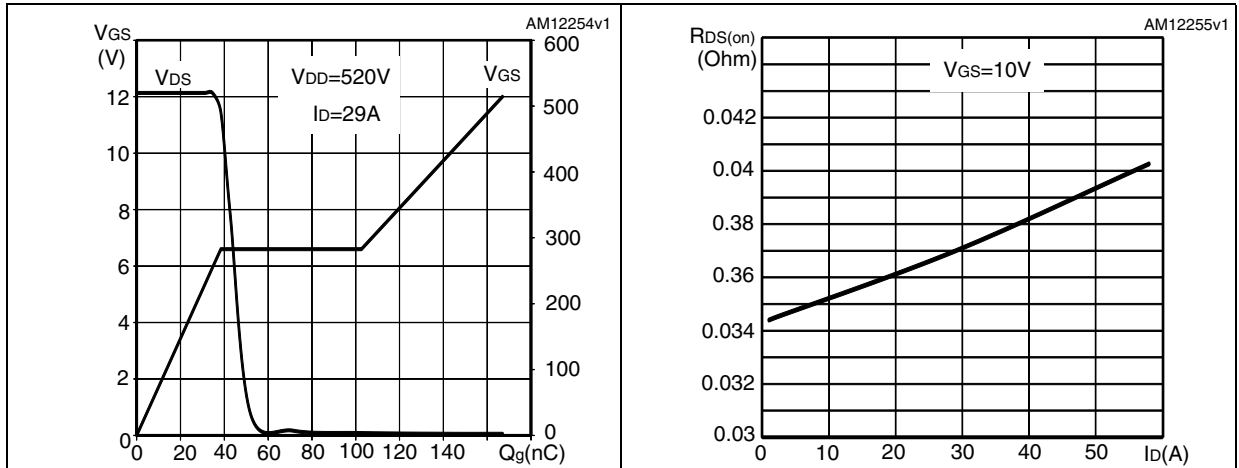


Figure 10. Capacitance variations Figure 11. Output capacitance stored energy

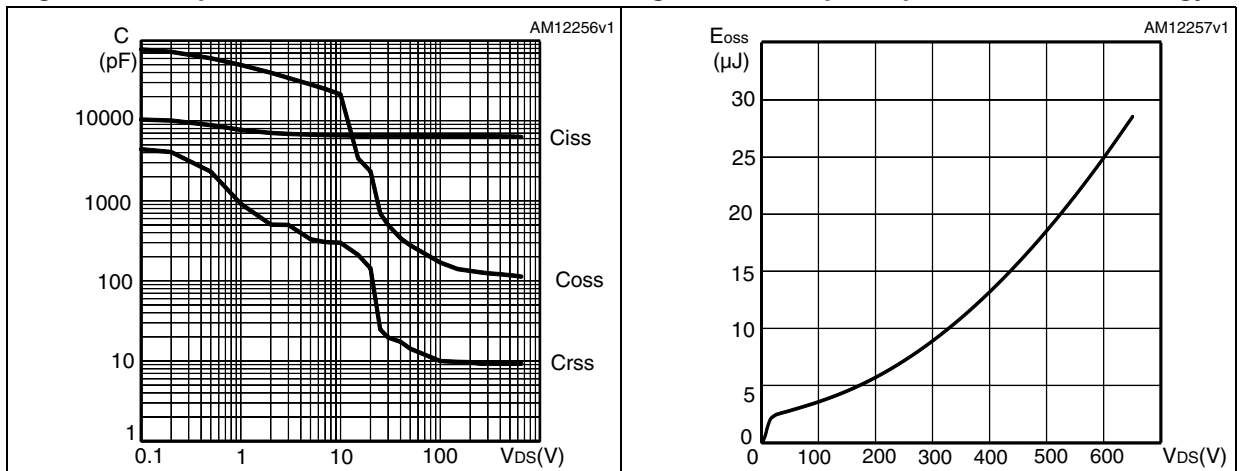


Figure 12. Normalized gate threshold voltage vs temperature Figure 13. Normalized on-resistance vs temperature

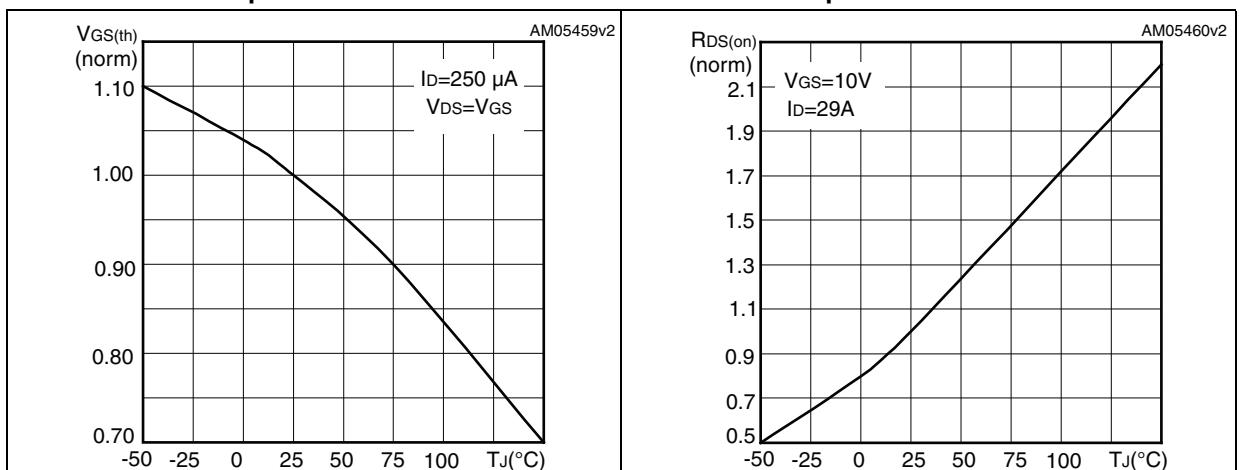


Figure 14. Source-drain diode forward characteristics

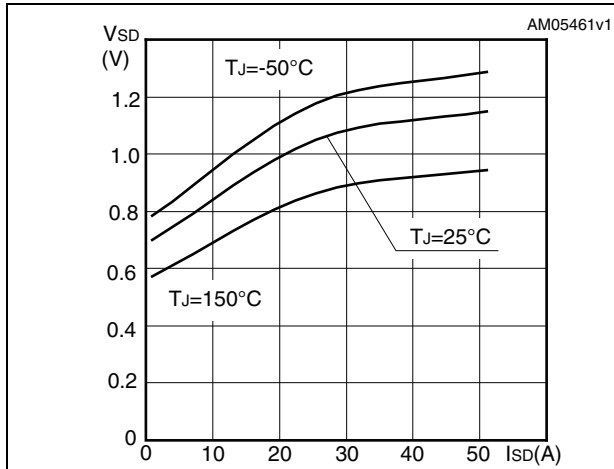


Figure 15. Normalized B_{VDSS} vs temperature

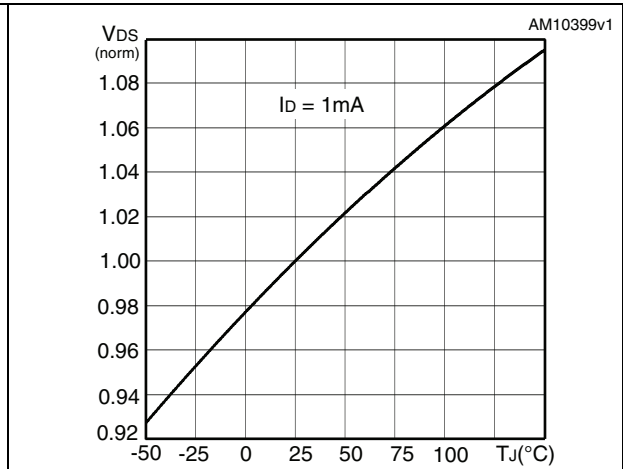
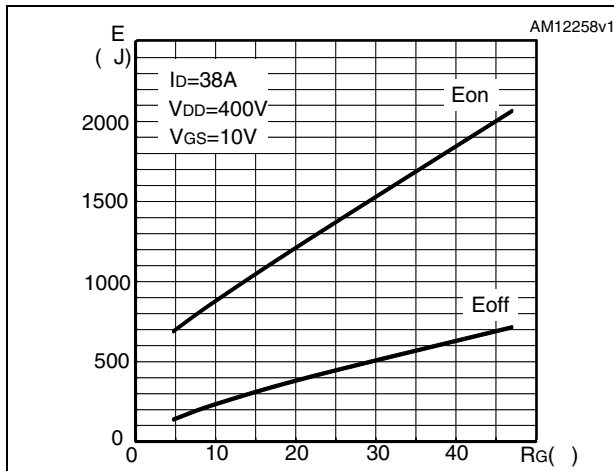


Figure 16. Switching losses vs gate resistance⁽¹⁾



1. Eon including reverse recovery of a SiC diode

3 Test circuits

Figure 17. Switching times test circuit for resistive load

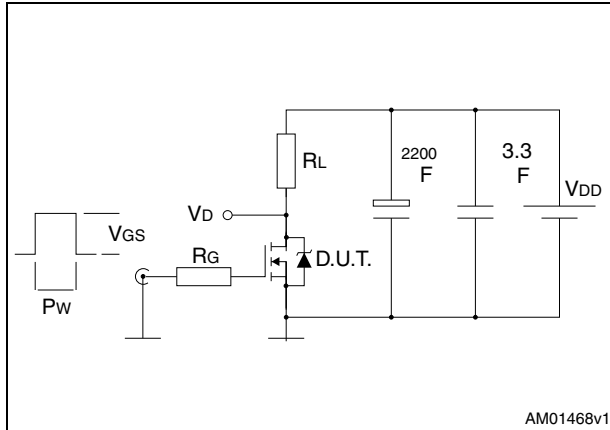


Figure 18. Gate charge test circuit

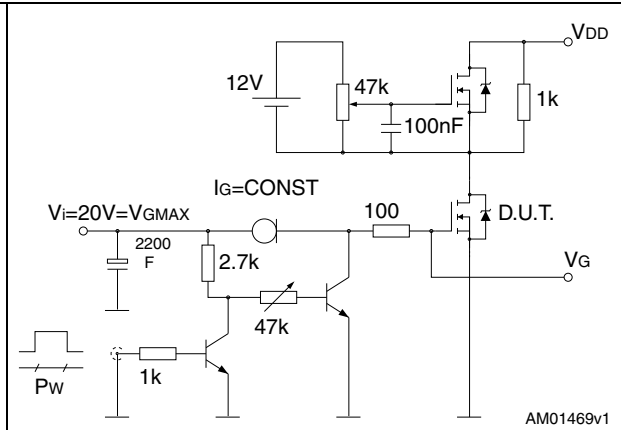


Figure 19. Test circuit for inductive load switching and diode recovery times

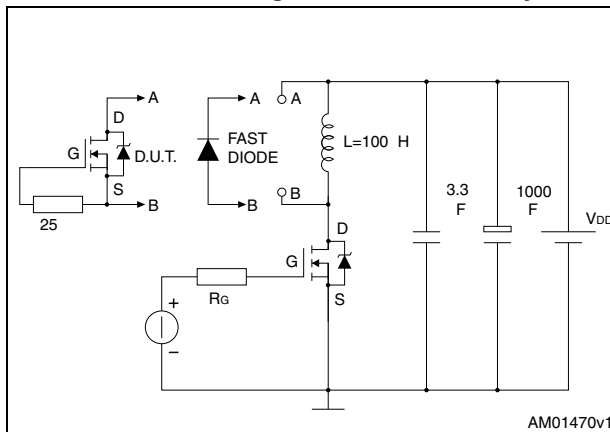


Figure 20. Unclamped inductive load test circuit

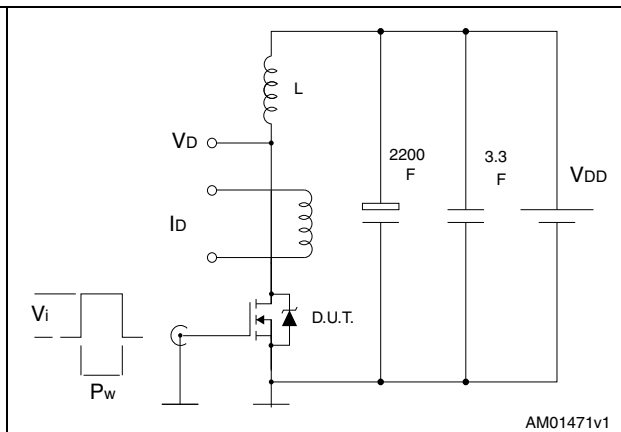


Figure 21. Unclamped inductive waveform

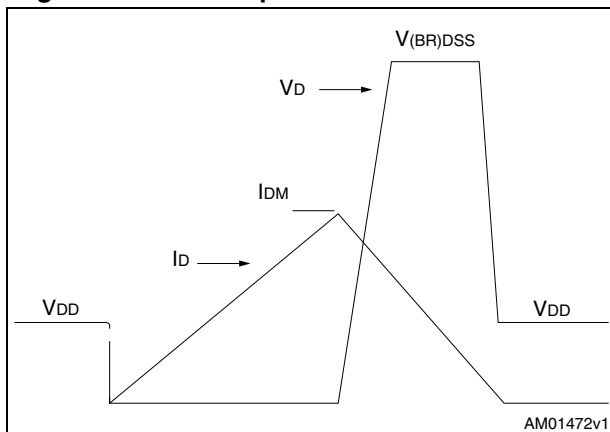
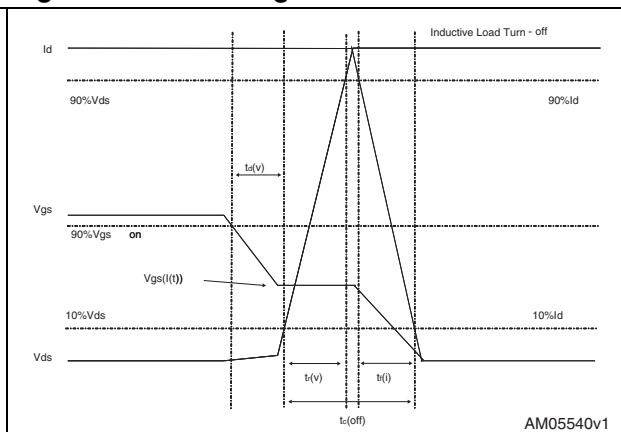


Figure 22. Switching time waveform



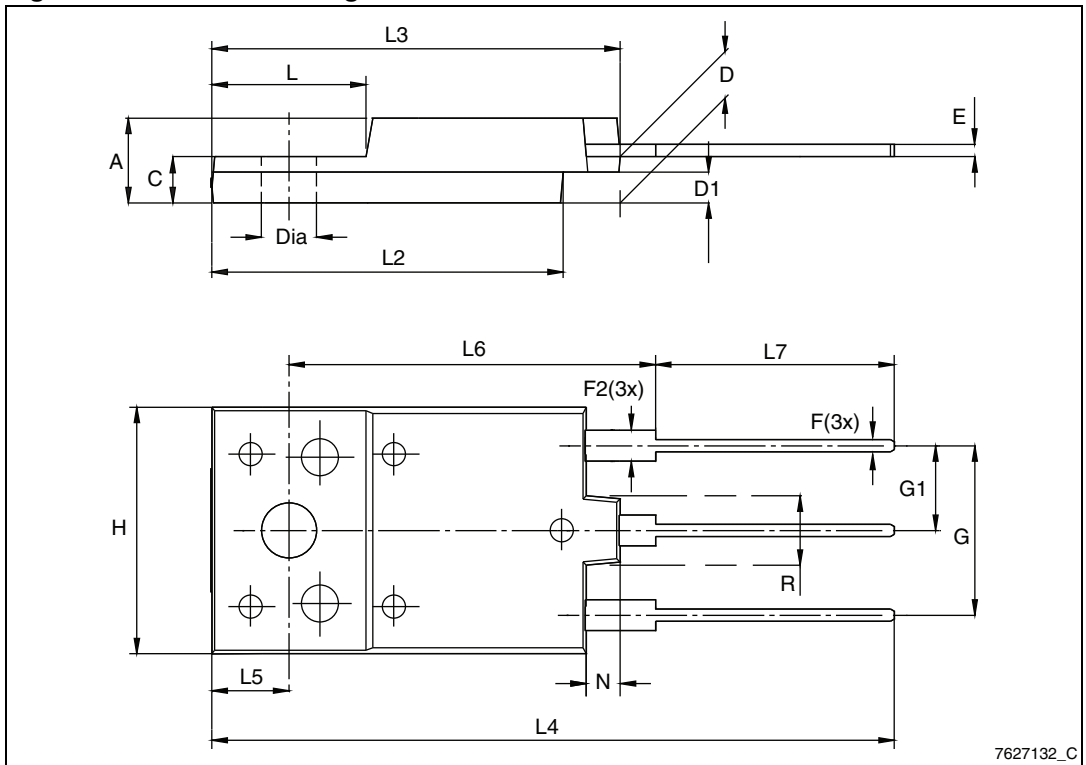
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK[®] is an ST trademark.

Table 9. TO-3PF mechanical data

| Dim. | mm | | |
|------|-------|------|-------|
| | Min. | Typ. | Max. |
| A | 5.30 | | 5.70 |
| C | 2.80 | | 3.20 |
| D | 3.10 | | 3.50 |
| D1 | 1.80 | | 2.20 |
| E | 0.80 | | 1.10 |
| F | 0.65 | | 0.95 |
| F2 | 1.80 | | 2.20 |
| G | 10.30 | | 11.50 |
| G1 | | 5.45 | |
| H | 15.30 | | 15.70 |
| L | 9.80 | 10 | 10.20 |
| L2 | 22.80 | | 23.20 |
| L3 | 26.30 | | 26.70 |
| L4 | 43.20 | | 44.40 |
| L5 | 4.30 | | 4.70 |
| L6 | 24.30 | | 24.70 |
| L7 | 14.60 | | 15 |
| N | 1.80 | | 2.20 |
| R | 3.80 | | 4.20 |
| Dia | 3.40 | | 3.80 |

Figure 23. TO-3PF drawing

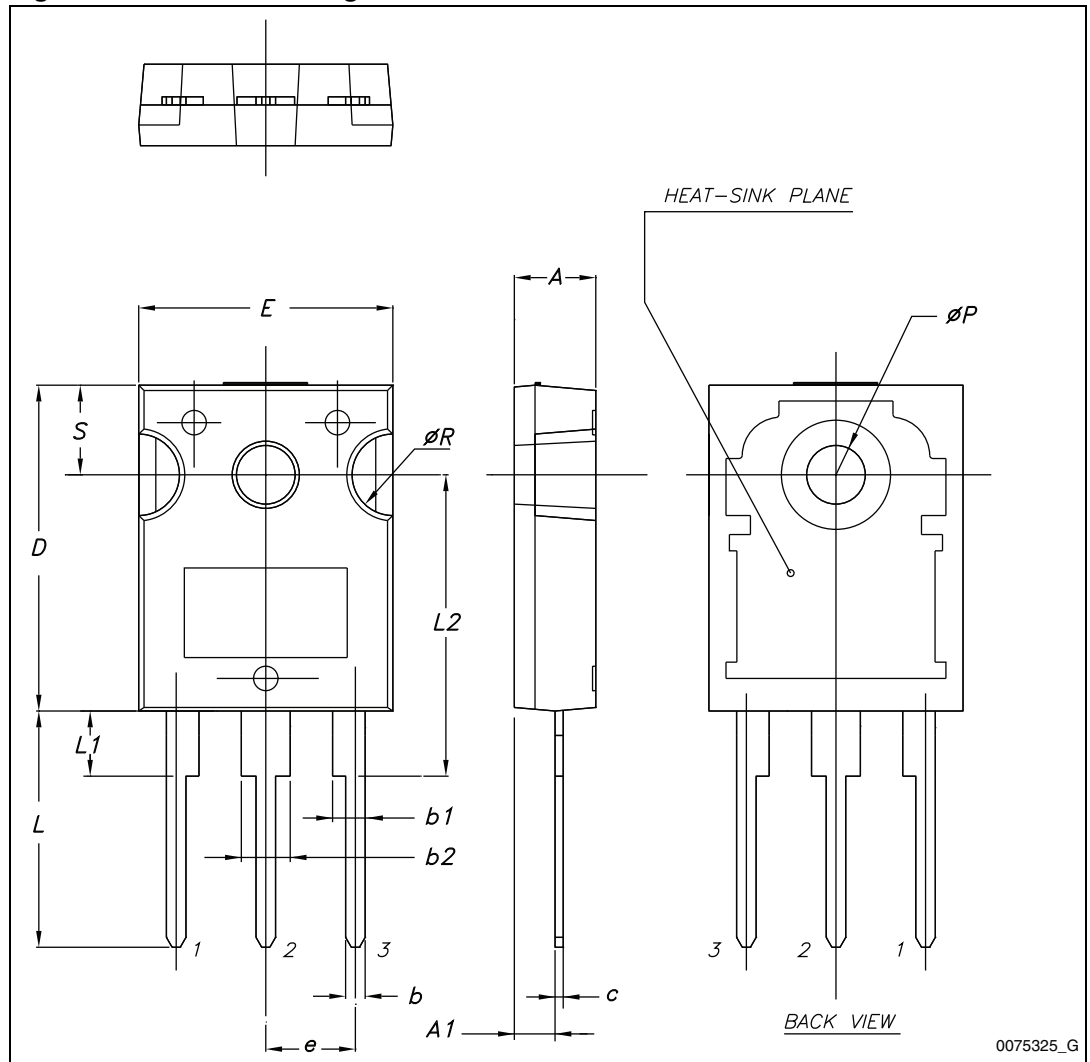


7627132_C

Table 10. TO-247 mechanical data

| Dim. | mm. | | |
|------|-------|-------|-------|
| | Min. | Typ. | Max. |
| A | 4.85 | | 5.15 |
| A1 | 2.20 | | 2.60 |
| b | 1.0 | | 1.40 |
| b1 | 2.0 | | 2.40 |
| b2 | 3.0 | | 3.40 |
| c | 0.40 | | 0.80 |
| D | 19.85 | | 20.15 |
| E | 15.45 | | 15.75 |
| e | 5.30 | 5.45 | 5.60 |
| L | 14.20 | | 14.80 |
| L1 | 3.70 | | 4.30 |
| L2 | | 18.50 | |
| ØP | 3.55 | | 3.65 |
| ØR | 4.50 | | 5.50 |
| S | 5.30 | 5.50 | 5.70 |

Figure 24. TO-247 drawing



5 Revision history

Table 11. Document revision history

| Date | Revision | Changes |
|-------------|----------|--|
| 27-Feb-2012 | 1 | First release. |
| 28-Sep-2012 | 2 | <ul style="list-style-type: none">– Modified: note 3 of Table 2, values in Table 4, typ. values in Table 6, 7 and 8– Curves inserted– Minor text changes |

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